

Product Change Notification - KSRA-05ATCO683

Date:

11 Mar 2019

Product Category:

Others; Linear Regulators

Affected CPNs:

Notification subject:

CCB 3454 and 3454.001 Initial Notice: Qualification of GTBF as a new assembly site for selected products of 0.8um XFAB, 0.8um AMS and 0.6um AMI, 130K and 133K wafer technologies available in 3L and 5L DDPAK packages with MSL 3 classification.

Notification text:
PCN Status:

Initial notification

PCN Type:

Manufacturing Change

Microchip Parts Affected:

Please open one of the icons found in the Affected CPNs section above.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change:

Qualification of GTBF as a new assembly site for selected products of 0.8um XFAB, 0.8um AMS and 0.6um AMI, 130K and 133K wafer technologies available in 3L and 5L DDPAK packages.

Pre Change:

Assembled at CARSEM using 84-1 LMISR4 die attach, CEL-9240HF10 molding compound and HCL-12S leadframe material with MSL 1 classification

Post Change:

Assembled at GTBF using CRM-1800 die attach, EME-G600 molding compound and LY80 leadframe material with MSL 3 classification

Pre and Post Change Summary:

	Pre Change	Post Change
Assembly Site	Carsem (M) SDN BHD (CARM)	Great Team Backend Foundry (Dong Guan) Ltd. (GTBF)
Wire material	Au wire	Au wire
Die attach material	84-1 LMISR4	CRM-1800
Molding compound material	CEL-9240HF10	EME-G600
Lead frame material	HCL-12S	LY80
MSL Classification	MSL 1	MSL 3

Impacts to Data Sheet:

None

Change Impact:

None

Reason for Change:

To improve on-time delivery performance by qualifying GTBF as a new assembly site. CARM assembly site will no longer have manufacturing support for the selected products.



Change Implementation Status:

In Progress

Estimated Qualification Completion Date:

April 2019

Note: Please be advised the qualification completion times may be extended because of unforeseen business conditions however implementation will not occur until after qualification has completed and a final PCN has been issued. The final PCN will include the qualification report and estimated first ship date. Also note that after the estimated first ship date guided in the final PCN customers may receive pre and post change parts.

Time Table Summary:

	August 2018					📅	April 2019				
Workweek	31	32	33	34	35	📅	14	15	16	17	18
Initial PCN Issue Date		X									
Qual Report Availability								X			
Final PCN Issue Date								X			

Method to Identify Change:

Traceability code

Qualification Plan:

Please open the attachments included with this PCN labeled as PCN_#_Qual Plan

Revision History:

August 10, 2018: Issued initial notification.

March 11, 2019: Re-issued initial notification. Updated the qual plan to change the MSL level classification and added hot temperature 125°C in selected reliability test.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachment(s):

[PCN_KSRA-05ATCO683_Qual_Plan.pdf](#)

Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to [receive Microchip PCNs via email](#) please register for our PCN email service at our [PCN home page](#) select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the [PCN FAQ](#) section.

If you wish to [change your PCN profile, including opt out](#), please go to the [PCN home page](#) select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

Affected Catalog Part Numbers (CPN)

MCP1790-3002E/EB
MCP1790-3302E/EB
MCP1790-5002E/EB
MCP1790T-3002E/EB
MCP1790T-3302E/EB
MCP1790T-3302E/EBVAO
MCP1790T-5002E/EB
MCP1790T-5002E/EBVAO
MCP1791-3002E/ET
MCP1791-3302E/ET
MCP1791-5002E/ET
MCP1791T-3002E/ET
MCP1791T-3302E/ET
MCP1791T-5002E/ET
MCP1825-0802E/ET
MCP1825-1202E/ET
MCP1825-1802E/ET
MCP1825-2502E/ET
MCP1825-3002E/ET
MCP1825-3302E/ET
MCP1825-5002E/ET
MCP1825-ADJE/ET
MCP1825S-0802E/EB
MCP1825S-1202E/EB
MCP1825S-1802E/EB
MCP1825S-2502E/EB
MCP1825S-3002E/EB
MCP1825S-3302E/EB
MCP1825S-5002E/EB
MCP1825ST-0802E/EB
MCP1825ST-1202E/EB
MCP1825ST-1802E/EB
MCP1825ST-2502E/EB
MCP1825ST-3002E/EB
MCP1825ST-3302E/EB
MCP1825ST-3302E/EBVAO
MCP1825ST-5002E/EB
MCP1825T-0802E/ET
MCP1825T-1202E/ET
MCP1825T-1802E/ET
MCP1825T-2502E/ET
MCP1825T-3002E/ET
MCP1825T-3302E/ET
MCP1825T-5002E/ET
MCP1825T-ADJE/ET
MCP1825T-ADJE/ETVAO

KSRA-05ATCO683 - CCB 3454 and 3454.001 Initial Notice: Qualification of GTBF as a new assembly site for selected products of 0.8um XFAB, 0.8um AMS and 0.6um AMI, 130K and 133K wafer technologies available in 3L and 5L DDPK packages with MSL 3 classification.

MCP1826-0802E/ET

MCP1826-1202E/ET

MCP1826-1802E/ET

MCP1826-2502E/ET

MCP1826-3002E/ET

MCP1826-3302E/ET

MCP1826-5002E/ET

MCP1826-ADJE/ET

MCP1826S-0802E/EB

MCP1826S-1202E/EB

MCP1826S-1802E/EB

MCP1826S-2502E/EB

MCP1826S-3002E/EB

MCP1826S-3302E/EB

MCP1826S-5002E/EB

MCP1826ST-0802E/EB

MCP1826ST-1202E/EB

MCP1826ST-1802E/EB

MCP1826ST-2502E/EB

MCP1826ST-3002E/EB

MCP1826ST-3302E/EB

MCP1826ST-5002E/EB

MCP1826T-0802E/ET

MCP1826T-1202E/ET

MCP1826T-1802E/ET

MCP1826T-2502E/ET

MCP1826T-3002E/ET

MCP1826T-3302E/ET

MCP1826T-5002E/ET

MCP1826T-ADJE/ET

MCP1827-0802E/ET

MCP1827-1002E/ET

MCP1827-1202E/ET

MCP1827-1802E/ET

MCP1827-2502E/ET

MCP1827-3002E/ET

MCP1827-3302E/ET

MCP1827-5002E/ET

MCP1827-ADJE/ET

MCP1827S-0802E/EB

MCP1827S-1002E/EB

MCP1827S-1202E/EB

MCP1827S-1802E/EB

MCP1827S-2502E/EB

MCP1827S-3002E/EB

MCP1827S-3302E/EB

MCP1827S-5002E/EB

MCP1827ST-0802E/EB

MCP1827ST-1002E/EB

KSRA-05ATCO683 - CCB 3454 and 3454.001 Initial Notice: Qualification of GTBF as a new assembly site for selected products of 0.8um XFAB, 0.8um AMS and 0.6um AMI, 130K and 133K wafer technologies available in 3L and 5L DDPAK packages with MSL 3 classification.

MCP1827ST-1202E/EB

MCP1827ST-1802E/EB

MCP1827ST-2502E/EB

MCP1827ST-3002E/EB

MCP1827ST-3302E/EB

MCP1827ST-5002E/EB

MCP1827T-0802E/ET

MCP1827T-1002E/ET

MCP1827T-1202E/ET

MCP1827T-1802E/ET

MCP1827T-2502E/ET

MCP1827T-3002E/ET

MCP1827T-3302E/ET

MCP1827T-5002E/ET

MCP1827T-ADJE/ET

TC1262-2.5VEB

TC1262-2.5VEBTR

TC1262-2.8VEB

TC1262-2.8VEBTR

TC1262-3.0VEB

TC1262-3.0VEBTR

TC1262-3.3VEB

TC1262-3.3VEBTR

TC1262-5.0VEB

TC1262-5.0VEBTR

TC1263-2.5VET

TC1263-2.5VETTR

TC1263-2.8VET

TC1263-2.8VETTR

TC1263-3.0VET

TC1263-3.0VETTR

TC1263-3.3VET

TC1263-3.3VETTR

TC1263-5.0VET

TC1263-5.0VETTR

TC1264-1.8VEB

TC1264-1.8VEBTR

TC1264-2.5VEB

TC1264-2.5VEBTR

TC1264-3.0VEB

TC1264-3.0VEBTR

TC1264-3.3VEB

TC1264-3.3VEBTR

TC1265-1.8VET

TC1265-1.8VETTR

TC1265-2.5VET

TC1265-2.5VETTR

TC1265-3.0VET

TC1265-3.0VETTR

KSRA-05ATCO683 - CCB 3454 and 3454.001 Initial Notice: Qualification of GTBF as a new assembly site for selected products of 0.8um XFAB, 0.8um AMS and 0.6um AMI, 130K and 133K wafer technologies available in 3L and 5L DDPAK packages with MSL 3 classification.

TC1265-3.3VE1

TC1265-3.3VETTR



MICROCHIP

QUALIFICATION PLAN SUMMARY

PCN #: KSRA-05ATCO683

**Date:
July 13, 2018**

Qualification of GTBF as a new assembly site for selected products of 0.8um XFAB, 0.8um AMS and 0.6um AMI, 130K and 133K wafer technologies available in 5L DDPAK packages with MSL 3 classification. The selected products available in 3L DDPAK package will qualify by similarity (QBS)

Purpose: Qualification of GTBF as a new assembly site for selected products of 0.8um XFAB, 0.8um AMS and 0.6um AMI, 130K and 133K wafer technologies available in 5L DDPAK packages with MSL 3 classification. The selected products available in 3L DDPAK package will qualify by similarity (QBS)

MP code: _____ Y1AD34J7XB30
Part No.: _____ MCP1791-3002E/ET
BD No: _____ BDM-001893 rev.B
CCB No: _____ 3454 and 3454.001
Package:
Type/Pin: _____ 5L DDPAK
Width or Size: _____ n/a
Die thickness: _____ 15 mils
Die size: _____ 65.00 x 65.90 mils
MSL: _____ MSL-3@245C

Misc.	Assembly site	GTBF
	BD Number	BDM-001893 rev.A
	MP Code (MPC)	Y1AD34J7XB30
	Part Number (CPN)	MCP1791-3002E/ET
Lead-Frame	Paddle size	266 x 174 mils
	Material	LY80
	Surface	Spot Ag
	Treatment	None
	Process	Stamped
	Lead-lock	Yes
	Part Number	A1-TO263-5-1CFAG
	LF Thickness	50 mils Pad:1.27mm/Lead:0.381mm (Dual Gauge LF)
Lead Plating	Matte Tin	
Bond Wire	Material	Au
Die Attach	Part Number	CRM-1800
	Conductive	Yes
MC	Part Number	EME-G600
PKG	PKG Type	DDPAK
	Pin/Ball Count	5
	PKG width/size	n/a
Die	Die Thickness	15 mils
	Die Size	65.00 x 65.90 mils

Test Name	Conditions	Reliability Stress Read Point	Pre & Post Reliability Stress Test Temperature	Sample Size	Min. Qty of Spares per Lot (should be properly marked)	Qty of Lots	Total Units	Fail Accept Qty	Est. Dur. Days	ATE Test Site	REL Test Site	Pkg. Type	Special Instructions
Standard Pb-free Solderability	J-STD-002D ; Perform 8 hours of steam aging for Matte tin finish and 1 hour steam aging for NiPdAu finish prior to testing. Standard Pb-free: Matte tin/ NiPdAu finish, SAC solder, wetting temp 245°C for both SMD & through hole packages.	Grade 1: -40°C to +125°C	Grade 1: -40°C to +125°C	22	5	1	27	>95% lead coverage	5				Standard Pb-free solderability is the requirement. SnPb solderability (backward solderability- SMD reflow soldering) is required for any plating related changes and highly recommended for other package BOM changes.
Wire Bond Pull - WBP	Mil. Std. 883-2011			5	0	1	5	0 fails after TC	5				30 bonds from a min. 5 devices.
Wire Bond Shear - WBS	CDF-AEC-Q100-001			5	0	1	5		5				30 bonds from a min. 5 devices.
Physical Dimensions	Measure per JESD22 B100 and B108			10	0	3	30		5				
External Visual	Mil. Std. 883-2009/2010			All devices prior to submission for qualification testing	0	3	ALL	0	5				
HTSL (High Temp Storage Life)	JESD22-A103 +125, +150°C or +175°C	Grade 1: 500 hrs (+175°C)	Grade 1: +25°C, +125°C	45	5	1	50	0	21 - 83	MTAI	MTAI		Spares should be properly identified.

Test Name	Conditions	Reliability Stress Read Point	Pre & Post Reliability Stress Test Temperature	Sample Size	Min. Qty of Spares per Lot (should be properly marked)	Qty of Lots	Total Units	Fail Accept Qty	Est. Dur. Days	ATE Test Site	REL Test Site	Pkg. Type	Special Instructions
Preconditioning - Required for surface mount devices	J-STD-020JESD22-A113+150°C Bake for 24 hours, moisture loading requirements per MSL level + 3X reflow at peak reflow temperature per Jedec-STD-020E for package type. MSL-3 @245C	Grade 1: -40°C to +125°C	Grade 1: -40°C to +125°C	231	15	3	738	0	15	MTAI	MTAI		Spares should be properly identified. 77 parts from each lot to be used for HAST, Autoclave, Temp Cycle test.
HAST	JESD22-A101 or A110 +130°C/85% RH for 96 hrs or +110°C/85%RH for 264 hrs	Grade 1: 96 hrs (+130°C/85% RH)	Grade 1: +25°C, +125°C	77	5	3	246	0	10 - 14	MTAI	MTAI		Spares should be properly identified. Use the parts which have gone through Pre-conditioning.
UFAST	JESD22-A102, A118, or A101 +130°C/85% RH for 96 hrs or +110°C/85% RH for 264 hrs	Grade 1: 96 hrs (+130°C/85% RH)	Grade 1: +25°C	77	5	3	246	0	10	MTAI	MTAI		Spares should be properly identified. Use the parts which have gone through Pre-conditioning.
Temp Cycle	JESD22-A104 and Appendix 3 -55°C to +125°C, -55°C to +150°C or -65°C to +150°C	Grade 1: 500 cycles (-65°C to 150°C)	Grade 1: +125°C	77	5	3	246	0	15 - 60	MTAI	MTAI		Spares should be properly identified. Use the parts which have gone through Pre-conditioning.